

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.†	Document Number	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ‡ (if known)	MM-DD-YYYY		
	A354*	US-4,994,866	02-19-1991	Awano et al.	
	A355*	US-5,849,612	12-15-1998	Takahashi et al.	
	A356*	US-6,008,128	12-28-1999	Habuka et al.	
	A357*	US-6,593,625-A1	07-15-2003	Christiansen et al.	
	A358*	US-6,689,211	02-10-2004	Wu et al.	
	A359*	US-6,723,621	04-20-2004	Cardone et al.	
	A360*	US-6,727,550-A1	04-27-2004	Tezuka et al.	
	A361*	US-6,858,502-A1	02-22-2005	Chu et al.	
	A362*	US-6,879,053	04-12-2005	Welches et al.	
	A363*	US-6,881,632-A1	04-19-2005	Fitzgerald et al.	
	A364*	US-2002/0079427	06-27-2002	Xu et al.	
	A364*	US-6,444,578	09-03-2002	Cabral et al.	

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No.	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	†
		Country Code* -Number* -Kind Code* (if known)					

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T
C342	AmberWave Systems Corporation's Responses to Intel's Sixth Set of Interrogatories, C.A. No. 05-301-KAJ (consolidated) (September 5, 2006)		
C343	AmberWave Systems Corporation's Responses to Intel's Fifth Set of Requests for Production, Civil Action No. 05-301-KAJ (consolidated) (June 30, 2006)		
C344	AmberWave Systems Corporation's Responses to Intel's Fifth Set of Interrogatories, C.A. No. 05-301-KAJ (consolidated) (June 19, 2006)		
C345	AmberWave Systems Corporation's Responses to Intel's Third Set of Requests for Production, C.A. No. 05-301-KAJ (consolidated) (February 10, 2006)		
C346	AmberWave Systems Corporation's First Supplemental Responses to Intel's First Set of Interrogatories, C.A. No. 05-837-KAJ (July 12, 2006)		
C347	Bera et al., "Gas Source Molecular Beam Epitaxy Grown Strained-Si Films on Step-Graded Relaxed Si <sub>0.5</sub> Ge <sub>0.5</sub> for MOS Applications," 28 J. Electron. Mat. 2, pp. 98-104 (1999).		

Examiner Signature		Date Considered	
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Substitute for form 1449/PTO		<b>Complete if Known</b>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(Use as many sheets as necessary)</i>		<b>Application Number</b>	10/774,890-Conf. #8754
		<b>Filing Date</b>	February 9, 2004
		<b>First Named Inventor</b>	Eugene A. Fitzgerald
		<b>Art Unit</b>	2818
		<b>Examiner Name</b>	D. A. Le
<b>Sheet</b>	2	of	2
		<b>Attorney Docket Number</b>	ASC-049C1

C348	Corrected Request for Inter Partes Reexamination of U.S. Patent No 6,649,480, January 12, 2007.	
C349	Intel's Amended and Supplemented Responses and Objections to AmberWave's First Set of Interrogatories, Civil Action No. 05-301-KAJ (August 7, 2006)	
C350	Intel's Responses and Objections to AmberWave's First Set of Requests for Production, Civil Action No. 05-837-KAJ (February 3, 2006)	
C351	Intel's Amended Responses and Objections to AmberWave's First Set of Interrogatories, Civil Action No. 05-837-KAJ (February 3, 2006)	
C352	Intel's Responses and Objections to AmberWave's First Set of Interrogatories, Civil Action No. 05-837-KAJ (February 3, 2006)	
C353	International Search Report for International Patent Application No PCT/US01/46322, mailed 1/22/2003.	
C354	John et. al., "Strained Si n-channel metal-oxide-semiconductor transistor on relaxed Si <sub>1-x</sub> Ge <sub>x</sub> formed by Ion Implantation of Ge," 74 Applied Physics Letters 14, pp. 2076-78 (1999).	
C355	Office action in Inter Partes Reexamination of U.S. Patent No. 6,649,480, March 23, 2007.	
C356	Request for Inter Partes Reexamination of U.S. Patent No. 6,649,480, October 24, 2006.	
C357	Wolf and Tauber, Silicon Processing for the VLSI Era Volume 1: Process Technology, Lattice Press, Sunset Beach, CA, 1986, pp. 124-160.	

LIBC/3216291

<b>Examiner Signature</b>	<b>Date Considered</b>
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